Invited paper

Something I Always Wanted to Know About Test, But Was Afraid to Ask

Christian Landrault

Christian Landrault received the Engineering degree from the Higher National School for Aeronautical Constructions (ENSICA), Toulouse, France in 1970, the Doctor in Engineering degree in Automatic Control, and the Doctor es-sciences degree in Computer Science from the National Polytechnic Institute of Toulouse, in 1973 and 1977, respectively. He is a "Directeur de Recherche" at CNRS ("National scientific Research Center"). He joined LAAS-CNRS in Toulouse in 1970 where he was a member of the Fault Tolerance and Dependable Computing research group until late 1980. From 1970 to 1980, he worked on self checking circuits, dependability architecture and dependability evaluation of digital systems. From 1980 to April 2009, he was working with LIRMM ("Laboratoire d'Informatique de Robotique et de Microélectronique de Montpellier", http://www.lirmm.fr) where he was head of the Microelectronics research Department till January 2001. C. Landrault's scientific interests included fault modelling, digital and memory testing, fault simulation, ATPG, design for testability and BIST. He is now on retirement and his main interests include (but are not limited to) fly fishing, mushrooming, Rose and Joséphine.

Abstract: As pinpointed in the last ITRS report and also clearly highlighted in the past years test conference programs, the overall mission of manufacturing test is continuously shifting from its "screening defects" basic and primary objective towards more subtle and secondary goals constituted for example by reliability aspect and yield learning. Just after his retirement, the author examines these new testing opportunity and will try to give directions to all what he missed and failed to do in his research career.